

ABSTRACT OF THE DISCLOSURE

An array test is performed during the process of panel formation, such as at a stage where a driving TFT which supplies a drive current for an organic EL element is completed and an anode of the organic EL element has been formed on the TFT. Then, with regard to a defective pixel, a line connecting the driving TFT and the anode is disconnected using a laser.

After the line has been thus disconnected, a planarization insulating film is formed, and this film fills the holes caused by the laser irradiation. It is thus possible to suppress deterioration of pixels and also effectively darken a defective pixel using laser.